

US00D628709S

(12) **United States Design Patent**
Burdett, Jr. et al.

(10) **Patent No.:** **US D628,709 S**
(45) **Date of Patent:** **** Dec. 7, 2010**

(54) **SAMPLE CELL FOR X-RAY ANALYZER**
(75) Inventors: **John H. Burdett, Jr.**, Charlton, NY (US); **Daniel L. Dunham**, Averill Park, NY (US); **James B. Quinn**, Ravena, NY (US)

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(73) Assignee: **X-Ray Optical Systems, Inc.**, East Greenbush, NY (US)

(**) Term: **14 Years**

(21) Appl. No.: **29/359,297**

(22) Filed: **Apr. 8, 2010**

Related U.S. Application Data

(63) Continuation of application No. 29/298,204, filed on Nov. 30, 2007, now abandoned.

(51) **LOC (9) Cl.** **24-01**

(52) **U.S. Cl.** **D24/216**

(58) **Field of Classification Search** D24/216,
D24/222-226, 227, 229, 230, 231, 232, 169,
D24/112-114, 130; D10/81; D3/203.1-203.8;
422/99, 102; D9/503, 504, 505, 529, 530,
D9/549; 435/288.1, 288.3, 288.4, 304.1,
435/305.1, 305.3, 305.4; 604/195, 218, 232
See application file for complete search history.

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Primary Examiner—T. Chase Nelson
Assistant Examiner—Anhdao Doan
(74) *Attorney, Agent, or Firm*—Jeffrey Klembczyk, Esq.; Kevin P. Radigan, Esq.; Heslin Rothenberg Farley & Mesiti P.C.

(57) **CLAIM**

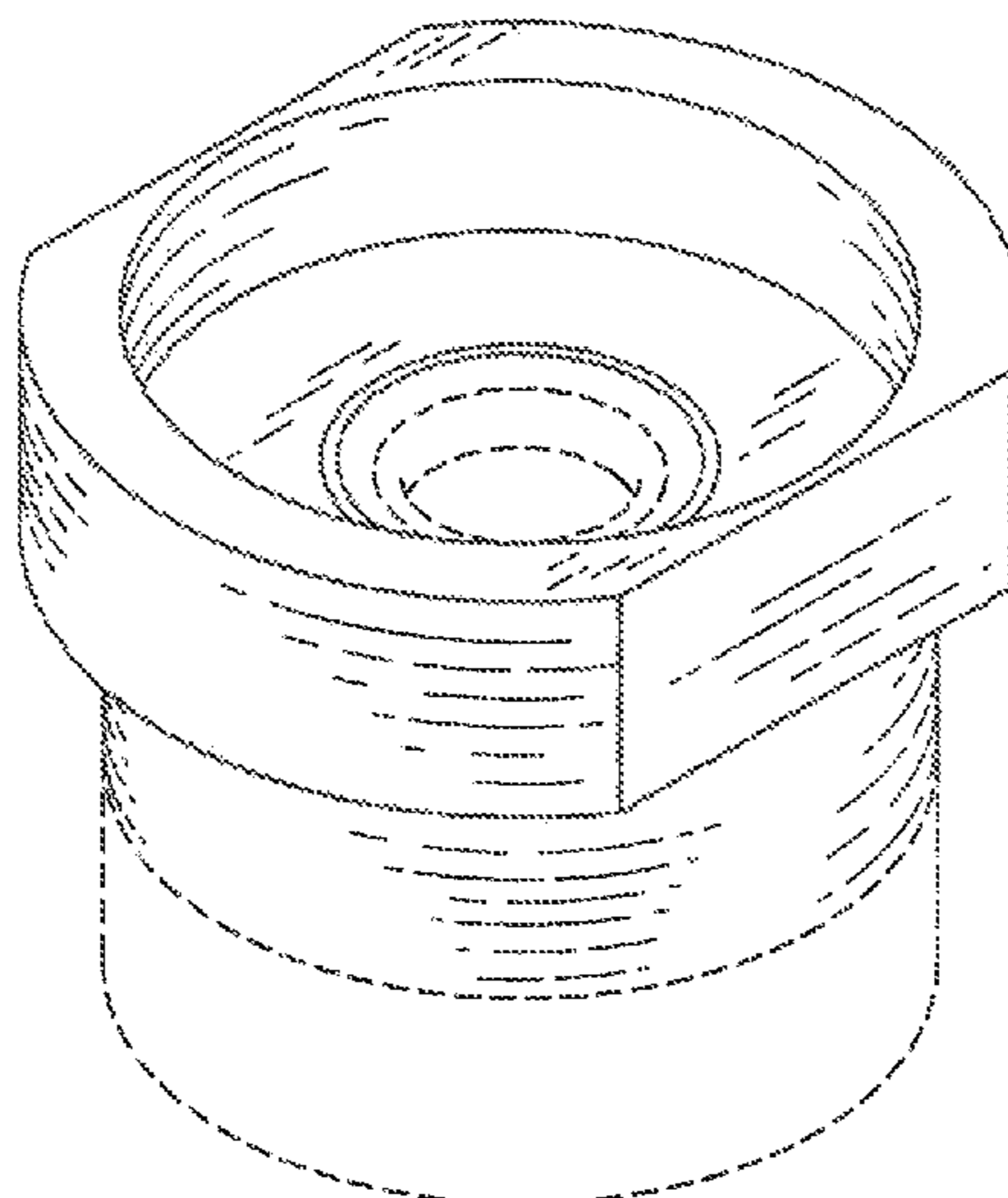
The ornamental design for a sample cell for x-ray analyzer, as shown and described.

DESCRIPTION

FIG. 1 is a first perspective view of a sample cell for x-ray analyzer comprising the new design;
FIG. 2 is second perspective view thereof;
FIG. 3 is a front side elevational view thereof, the rear side elevational view being a mirror image thereof;
FIG. 4 is a right side elevational view thereof, the left side elevational view being a mirror image thereof;
FIG. 5 is a top view thereof; and,
FIG. 6 is a bottom view thereof.

The broken lines in the drawing views are included for the purpose of illustrating portions of the sample cell for x-ray analyzer that form no part of the claimed design.

1 Claim, 3 Drawing Sheets



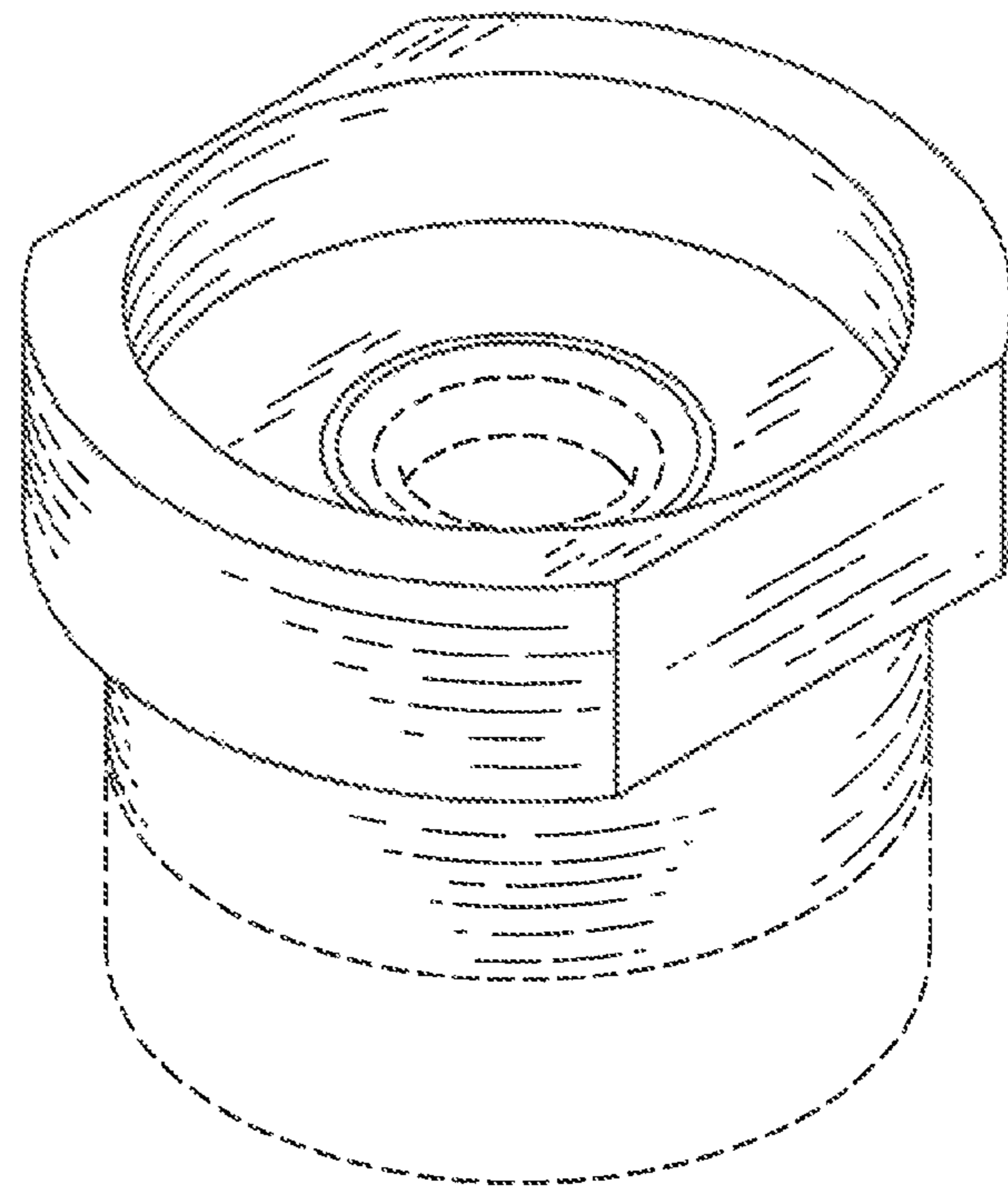


FIG. 1

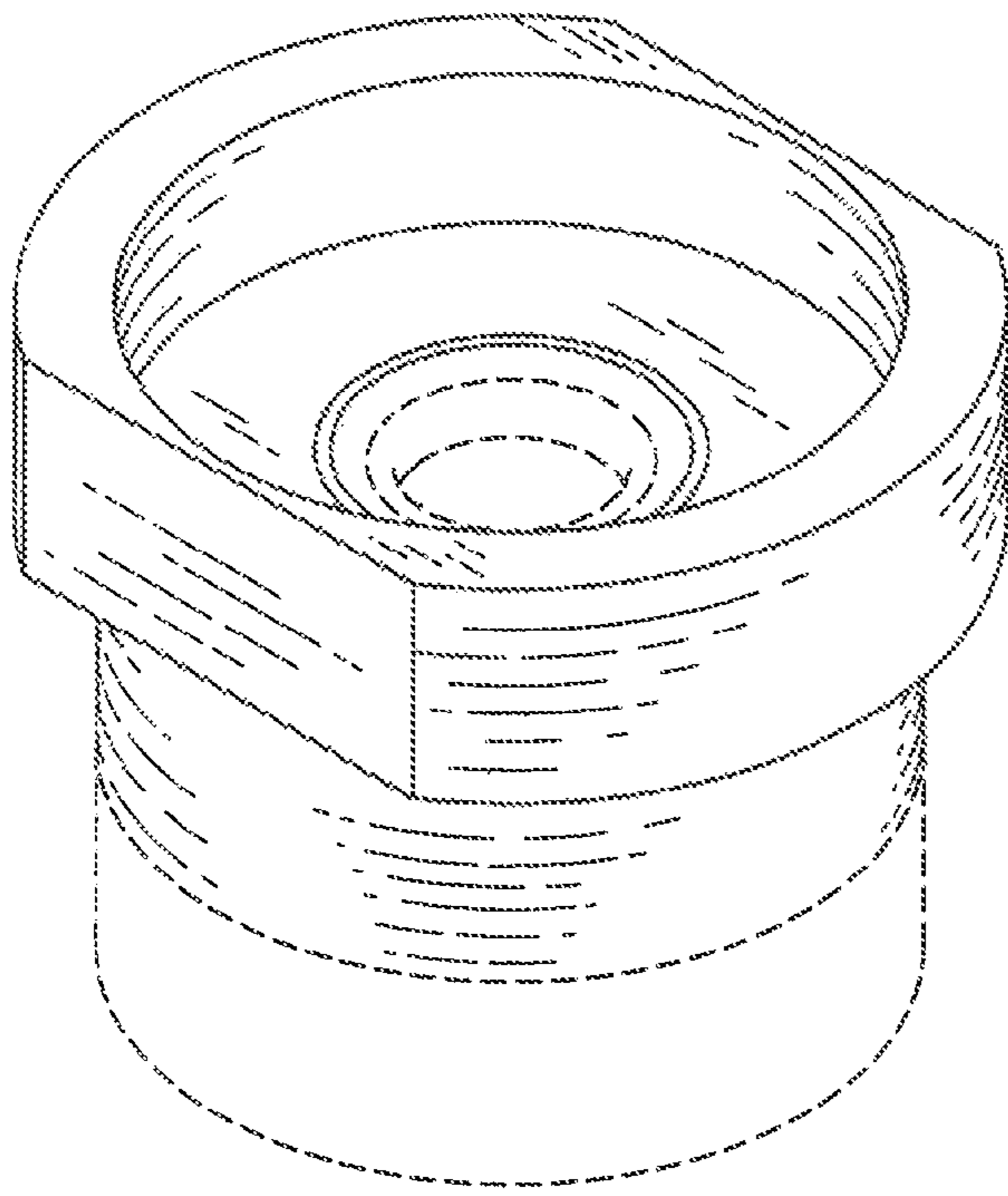


FIG. 2

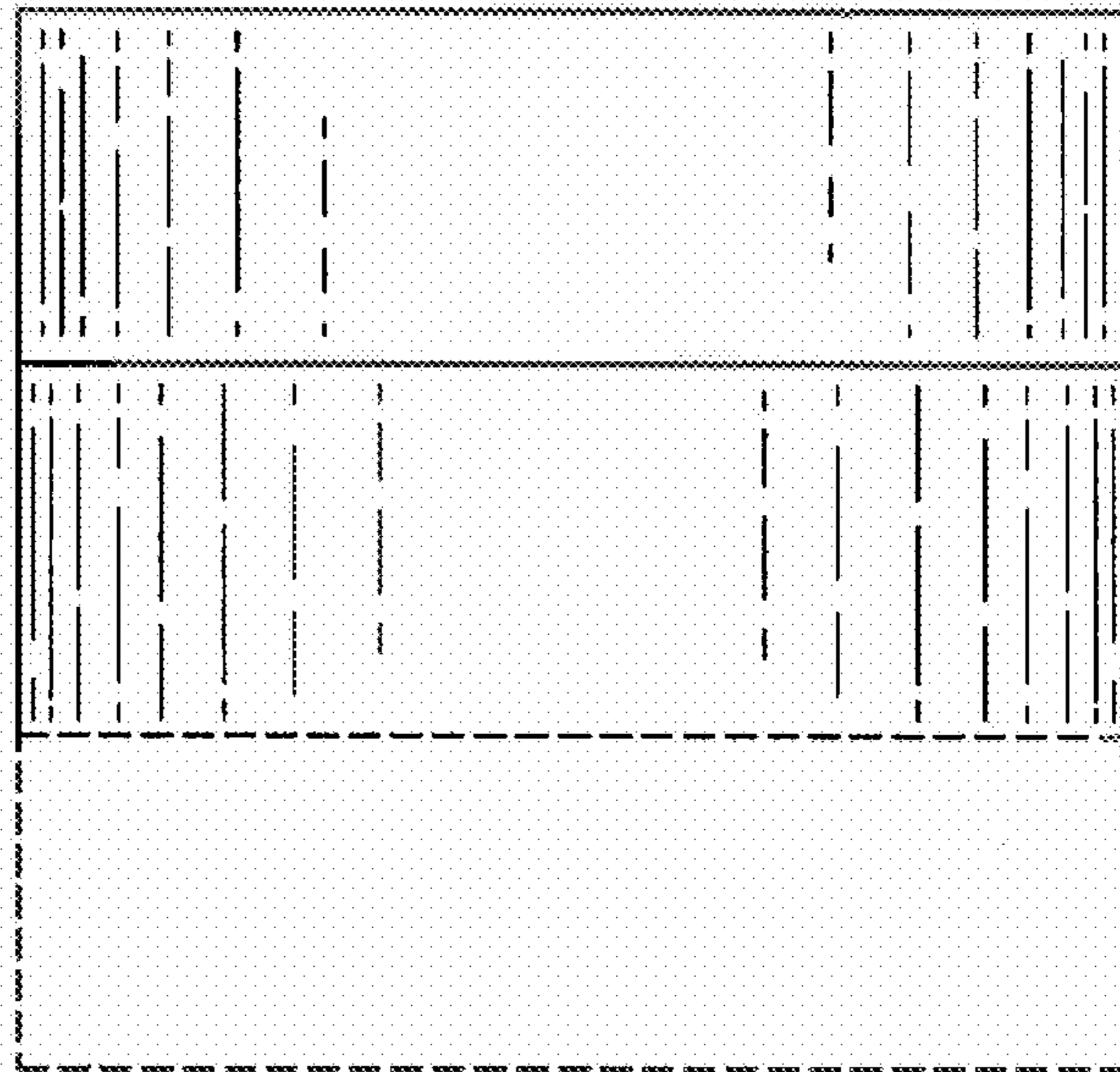


FIG. 3

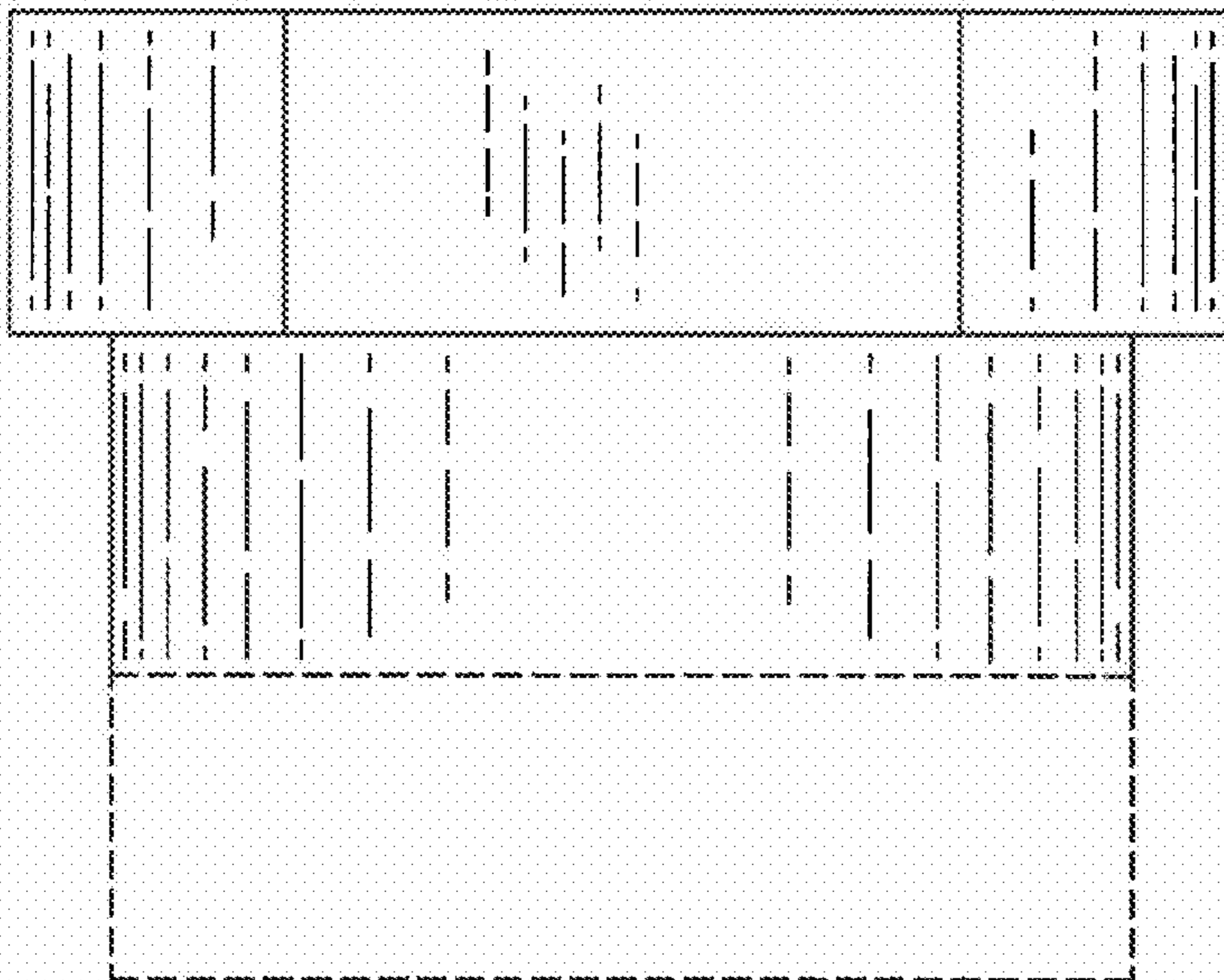


FIG. 4

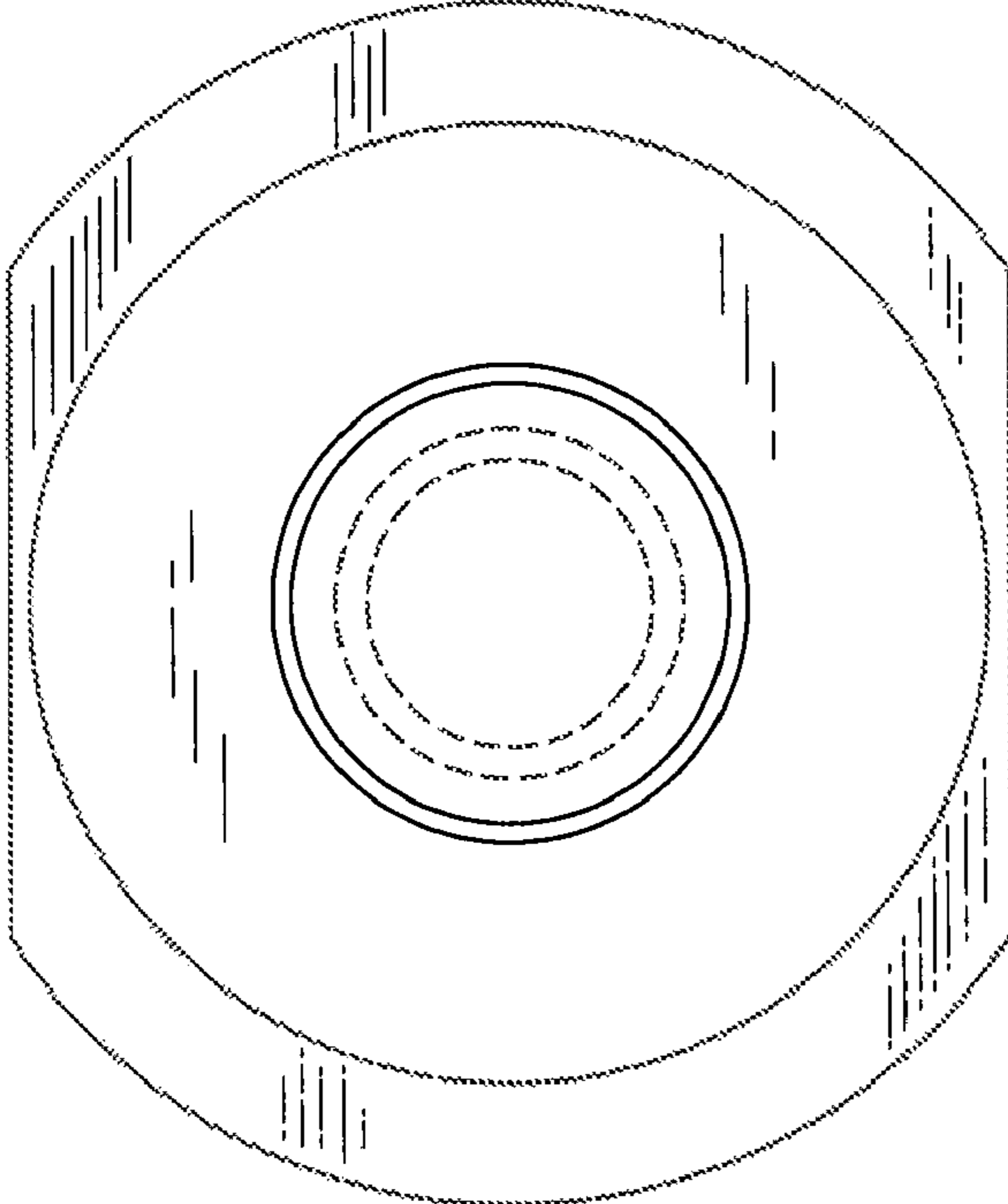


FIG. 5

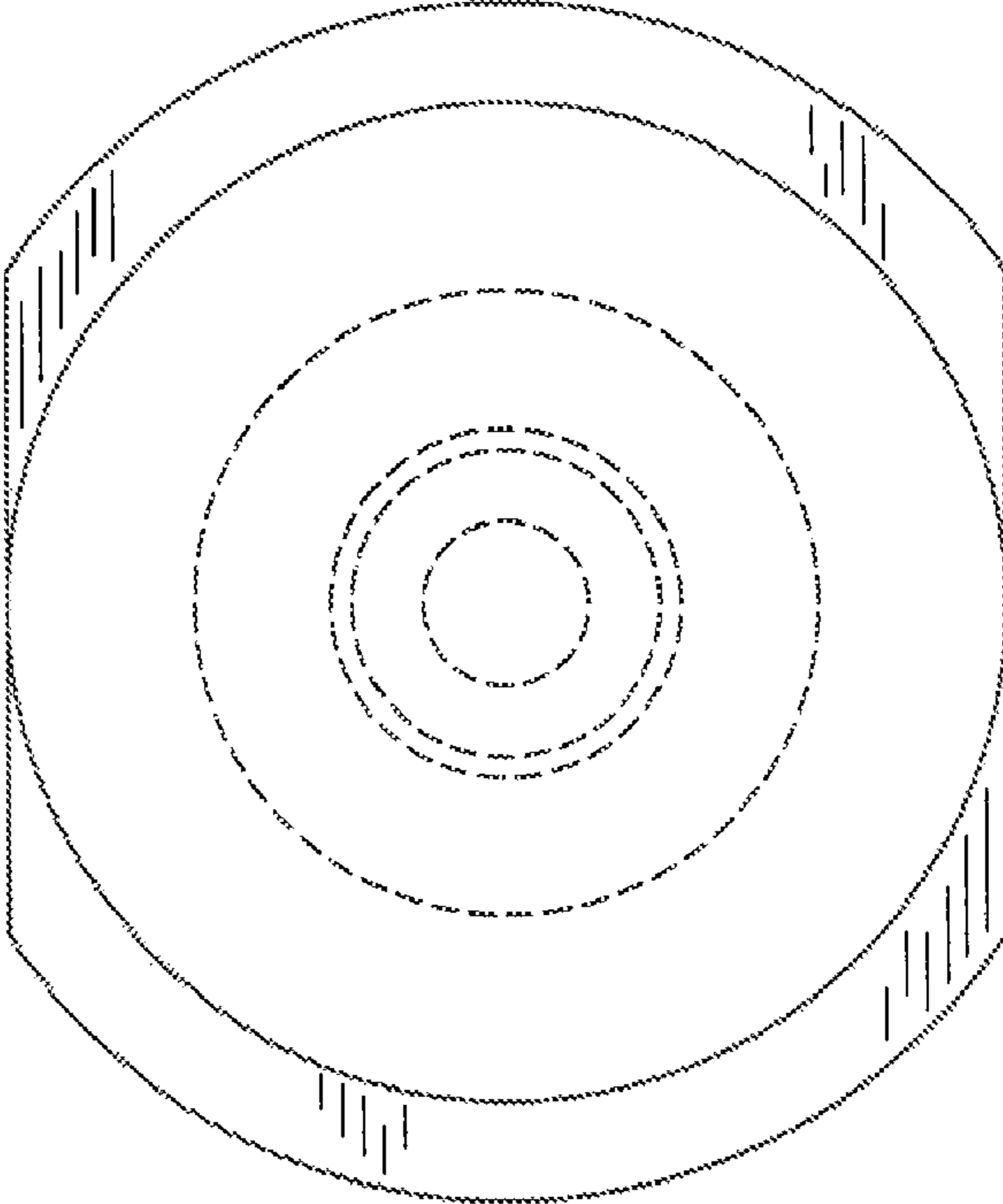


FIG. 6